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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/045,416	10/26/2001	David J. Kunst	A-70429/ENB	9958	
7590 02/03/2005			EXAMINER		
FLEHR HOHBACH TEST ALBRITTON & HERBERT LLP			DEB, ANJAN K		
Suite 3400 Four Embarcade	ero Center		ART UNIT	PAPER NUMBER	
San Francisco, CA 94111-4187			2858		
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Please find below and/or attached an Office communication concerning this application or proceeding.

SUPPLEMENTAL
Notice of Allowability

Application No.	Applicant(s)	
10/045,416	KUNST ET AL.	
Examiner	Art Unit	
Anjan K Deb	2858	

	Anjan K Deb	2858	
The MAILING DATE of this communication appearable daims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) of NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIC of the Office or upon petition by the applicant. See 37 CFR 1.313	OR REMAINS) CLOSED in this apport of the properties of the communication of the communication is subject to the communication in the communication is subject.	plication. If not include will be mailed in due	ed course. THIS
1. X This communication is responsive to RCE and amendment	filed 12/20/2004.		
2. ☑ The allowed claim(s) is/are <u>5,6,23-29,31 and 41-69</u> .			
3. The drawings filed on are accepted by the Examiner.			
 4. Acknowledgment is made of a claim for foreign priority under a) All b) Some* c) None of the: Certified copies of the priority documents have Certified copies of the priority documents have Copies of the certified copies of the priority documents have Copies of the certified copies of the priority documents have Copies of the certified copies of the priority documents have * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONME. 	been received. been received in Application No uments have been received in this of this communication to file a reply	national stage applica	
 THIS THREE-MONTH PERIÓD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give: 			OTICE OF
6. CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspersor 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1.6 each sheet. Replacement sheet(s) should be labeled as such in the T. DEPOSIT OF and/or INFORMATION about the depose attached Examiner's comment regarding REQUIREMENT F.	Amendment / Comment or in the Comment or in the Comment or in the Comment or the drawing header according to 37 CFR 1.121(Office action of ngs in the front (not the d). The nust be submitted.	
 Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☑ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date	5. Notice of Informal F 6. Interview Summary Paper No./Mail Da 7. Examiner's Amenda 8. Examiner's Statema 9. Other	(PTO-413), te ment/Comment	

1. This office action is in response to RCE and amendment filed 12/20/2004.

Allowable Subject Matter

2. Claims 5,6,23-29,31,41-69 are allowed.

Reasons for Allowance

3. The following is an examiner's statement of reasons for allowance:

The primary reason for allowance of the claims 5,6,23-27,41-45,49-69 is the inclusion of a dependent measurable current source coupled with the scaled reference current source for generating a measured current whereby the amount of measured current is a function of a first voltage drop across the measurable circuit element and the state of measurable circuit element is determined by the difference between the scaled reference current and the measured current.

The primary reason for allowance of the claims 28,29,31,46-48, is the inclusion of replicate element coupled with the adjustable test current source for receiving the adjustable test current so as to result in a second voltage drop across the replicate element whereby a voltage at one terminal of the replicate element is compared with a second sense voltage to provide a feedback to adjust the adjustable test current.

Audy (US 6,246,243 B1) disclosed apparatus (Fig. 2) for determining a state of a measurable circuit element (L1) having plurality of states (intact, blown) and a different

Art Unit: 2858

impedance in each state comprising a replicate circuit (Q3, Q5, Rth) configured to generate a test current and a trim determination circuit (Q4,Q6,LOGIC OUTPUT) including the measurable circuit element (L1) coupled with the replication circuit for receiving the test current (i_{det}) and indicating (LOGIC OUTPUT) at least one of the states of the measurable circuit element (L1). Audy lacks scaled reference current source for generating a measured current whereby the amount of measured current is a function of a first voltage drop across the measurable circuit element (L1).

Johnson (US 5,059,916) disclosed (Fig. 5) apparatus for determining a state of a measurable circuit element 14 having a plurality of states and a different impedance (variable resistance) in each state comprising a replicate circuit (35,34,32,33) configured to generate an adjustable test current and a trim determination circuit (36,14) coupled with the replication circuit for receiving the adjustable test current. Johnson lacks scaled reference current source for generating a measured current whereby the amount of measured current is a function of a first voltage drop across the measurable circuit element (14).

Pertinent art

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Arnoldi et al. (US 4,041,388) disclose circuit for determining a state of a measurable circuit element (transistor)(19) having a plurality of states comprising a replicate circuit 13 (Figure).

Genova (US 20020063573 A1) discloses circuit for monitoring the current delivered through a power transistor (NMOS_POWER), comprising a replicate circuit with an image transistor (NMOS_POWER_{SENSE}) that produces on a sensing node a scaled-down replica current of the current being delivered through the power transistor.

Thiery, Vincent (US 20040227539 A1) discloses circuit (Fig. 3) for determining a state of a measurable circuit element (LOAD) comprising replicate circuit 20B coupled to scaled reference current source 109.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Art Unit: 2858

Contact Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dr. Anjan K. Deb whose telephone number is (571)-272-2228. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, N. Le, can be reached at (571)272-2233.

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Art Unit: 2858

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2/2/05